

<b>Notice of References Cited</b>		Application/Control No. 10/788,989	Applicant(s)/Patent Under Reexamination O'NEIL ET AL.	
		Examiner Dan Washburn	Art Unit 2628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,737,394	04-1998	Anderson et al.	379/88.11
*	B	US-2002/0183098	12-2002	Lee et al.	455/566
*	C	US-2004/0253976	12-2004	Lin, Hsien-Chung	455/550.1
*	D	US-6,762,740	07-2004	Kimura, Etsuko	345/102
*	E	US-5,425,077	06-1995	Tsoi, Kam-Cheong A.	455/566
*	F	US-2002/0158915	10-2002	Rowell et al.	345/835
*	G	US-6,690,955	02-2004	Komiyama, Takehiko	455/566
*	H	US-7,203,522	04-2007	Hama et al.	455/566
*	I	US-2004/0072589	04-2004	Hamamura et al.	455/550.1
*	J	US-7,151,953	12-2006	Hamada et al.	455/567
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.